Issue Classification

Application/Control No. 10/606,487	**Applicant(s)/Patent under Reexamination** GEE ET AL.
Examiner Anthony Fick	**Art Unit** 1753

ISSUE CLASSIFICATION

ORIGINAL		CROSS REFERENCE(S)	
CLASS	**SUBCLASS**	**CLASS**	**SUBCLASS (ONE SUBCLASS PER BLOCK)**
136	256	136	252

INTERNATIONAL CLASSIFICATION

H	0	1	L	31/04
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Anthony Fick 9/12/06
(Assistant Examiner) (Date)

Wanda Mitchell
(Legal Instruments Examiner) (Date) 9/14/06

NAM NGUYEN
SUPERVISORY PATENT EXAMINER
TECHNOLOGY CENTER 1700
(Primary Examiner) (Date) 9/14/06

Total Claims Allowed: 15

O.G. Print Claim(s)	O.G. Print Fig.
1	1B

☐ Claims renumbered in the same order as presented by applicant   ☐ CPA   ☐ T.D.   ☐ R.1.47

Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original	Final	Original
1	1		31		61		91		121		151		181
2	2		32		62		92		122		152		182
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4	4		34		64		94		124		154		184
5	5		35		65		95		125		155		185
7	6		36		66		96		126		156		186
8	7		37		67		97		127		157		187
9	8		38		68		98		128		158		188
10	9		39		69		99		129		159		189
11	10		40		70		100		130		160		190
6	11		41		71		101		131		161		191
12	12		42		72		102		132		162		192
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	16		46		76		106		136		166		196
	17		47		77		107		137		167		197
	18		48		78		108		138		168		198
	19		49		79		109		139		169		199
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	21		51		81		111		141		171		201
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	27		57		87		117		147		177		207
	28		58		88		118		148		178		208
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	30		60		90		120		150		180		210